



Certificate of Conformity

No: S22052701202E

Low temperature test (MIL-STD-810H 2014 Method 502.7)

Applicant: Daten Tecnologia Ltda.
Address: Rodovia Ilheus/Urucuca Km 3,5, Iguape – CEP: 45.658-335 – Ilhéus – BA –Brazil
Sample Name: Notebook
Model No.: Daten DCM4A-4
Application Project: Low temperature test
Test Standards: MIL-STD-810H 2014 Method 502.7
Procedure: Procedure I (Storage)
Procedure II (Operation)
Test Parameters: 1. Non-operational -40°C
Four hours duration
2. Operational -21°C
Four hours duration
Judgment Result: Qualified

The Certificate of Compliance is based on a test procedure or evaluation of the above-mentioned product. This is to certify that the above-mentioned product is in compliance with the Low temperature testing standard (MIL-STD-810H 2014 Method 502.7).

Low temperature test

Signed for and on behalf of NTEK Ltd

Jun.14, 2022

Date

Manager:



Shenzhen NTEK Testing Technology Co., Ltd.

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